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**Search Results - Record(s) 1 through 4 of 4 returned.**☒ 1. Document ID: US 5493729 A**Using default format because multiple data bases are involved.**

L15: Entry 1 of 4

File: USPT

Feb 20, 1996

US-PAT-NO: 5493729

DOCUMENT-IDENTIFIER: US 5493729 A

TITLE: Knowledge data base processing system and expert system

DATE-ISSUED: February 20, 1996

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Nigawara; Seiitsu	Hitachi			JP
Namba; Shigeaki	Hitachi			JP
Kohmoto; Hiroshi	Hitachi			JP

US-CL-CURRENT: 706/52; 706/60

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Drawings
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☒ 2. Document ID: US 5005143 A

L15: Entry 2 of 4

File: USPT

Apr 2, 1991

US-PAT-NO: 5005143

DOCUMENT-IDENTIFIER: US 5005143 A

TITLE: Interactive statistical system and method for predicting expert decisions

DATE-ISSUED: April 2, 1991

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Altschuler; Martin D.	Wallingford	PA		
Whittington; Richard	Media	PA		

US-CL-CURRENT: 702/181; 706/46, 706/52, 706/924

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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☐ 3. Document ID: DE 4108310 A, JP 3268529 B2, US 5493729 A, DE 4108310 C2

L15: Entry 3 of 4

File: DWPI

Sep 26, 1991

DERWENT-ACC-NO: 1991-289202

DERWENT-WEEK: 200222

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TITLE: Knowledge base processing and expert system - stores indices representing certainty grade of casual relationship between occurrence and others relevant to it

INVENTOR: KOHMOTO, H; NAMBA, S ; NIGAWARA, S

PRIORITY-DATA: 1990JP-0063697 (March 14, 1990)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
<u>DE 4108310 A</u>	September 26, 1991		000	
<u>JP 3268529 B2</u>	March 25, 2002		019	G06F009/44
<u>US 5493729 A</u>	February 20, 1996		023	G06F015/18
<u>DE 4108310 C2</u>	October 22, 1998		000	G06F015/18

INT-CL (IPC): G06F 9/44; G06F 15/18

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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☐ 4. Document ID: US 5005143 A

L15: Entry 4 of 4

File: DWPI

Apr 2, 1991

DERWENT-ACC-NO: 1991-117187

DERWENT-WEEK: 199116

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TITLE: Interactive statistical system and predicting expert decisions - repeating random value generation and corresponding responses until sufficient are given to achieve set statistical significance

PRIORITY-DATA: 1989US-0411911 (September 25, 1989), 1987US-0065304 (June 19, 1987)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
<u>US 5005143 A</u>	April 2, 1991		000	

INT-CL (IPC): G06F 9/00; G06F 15/42

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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Terms	Documents
(5,005,143 5,493,729).pn.	4

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<u>L15</u>	(5,005,143 5,493,729).pn.	4	<u>L15</u>
<u>L14</u>	L13 and troubleshoot\$4	16	<u>L14</u>
<u>L13</u>	L12 and bayesian	63	<u>L13</u>
<u>L12</u>	diagnostic adj systems	3451	<u>L12</u>
<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>

L1 6,535,865.pn.

2 L1

END OF SEARCH HISTORY

## Hit List

Search Results - Record(s) 1 through 2 of 2 returned.

☐ 1. Document ID: US 5133046 A

Using default format because multiple data bases are involved.

L16: Entry 1 of 2

File: USPT

Jul 21, 1992

US-PAT-NO: 5133046

DOCUMENT-IDENTIFIER: US 5133046 A

TITLE: Computer-based diagnostic expert system organized according to Bayesian theory

DATE-ISSUED: July 21, 1992

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Kaplan; Stanley	Rancho Palas Verdes			CA

US-CL-CURRENT: 706/52; 706/912, 706/914

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KMC	Draw De
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☐ 2. Document ID: US 5133046 A

L16: Entry 2 of 2

File: DWPI

Jul 21, 1992

DERWENT-ACC-NO: 1992-268277

DERWENT-WEEK: 199232

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TITLE: Computer-based diagnostic expert system organised according to bayesian theory - generates diagnosis in form of probability distributions, responding to evidence in discrete time trajectories and data from knowledge base

INVENTOR: KAPLAN, S

PRIORITY-DATA: 1991US-0637190 (January 3, 1991)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
<u>US 5133046 A</u>	July 21, 1992		022	G06F015/18

INT-CL (IPC): G06F 15/18

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Drawings
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Terms	Documents
5,133,046.pn.	2

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### Search Results -

Terms	Documents
5,133,046.pn.	2

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<u>L16</u>	5,133,046.pn.	2	<u>L16</u>
<u>L15</u>	(5,005,143 5,493,729).pn.	4	<u>L15</u>
<u>L14</u>	L13 and troubleshoot\$4	16	<u>L14</u>
<u>L13</u>	L12 and bayesian	63	<u>L13</u>
<u>L12</u>	diagnostic adj systems	3451	<u>L12</u>
<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>



L2 4,866,635.pn.

2 L2

L1 6,535,865.pn.

2 L1

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<a href="#">A-Xin Nie</a>	<a href="#">A. C. Tsoi</a>	<a href="#">A. Fung</a>	<a href="#">A. LaRiviere H. J.</a>	<a href="#">A. I</a>
<a href="#">A. T. S. Wee</a>	<a href="#">Aa Johannessen E.</a>	<a href="#">Aa'lam N.</a>	<a href="#">Aaberg I. A.</a>	<a href="#">Aal</a>
<a href="#">Aabo Y.</a>	<a href="#">Aaby A. A.</a>	<a href="#">Aaccardo A.</a>	<a href="#">Aach T.</a>	<a href="#">Aac</a>
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<a href="#">Aagard E. G. R.</a>	<a href="#">Aagard R.</a>	<a href="#">Aage C.</a>	<a href="#">Aagedal H.</a>	<a href="#">Aag</a>
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#### 1 Probabilistic relevance relations

*Geiger, D.; Heckerman, D.;*

Systems, Man and Cybernetics, Part A, IEEE Transactions on , Volume: 28 , I  
1 , Jan. 1998

Pages:17 - 25

[\[Abstract\]](#) [\[PDF Full-Text \(560KB\)\]](#) **IEEE JNL**

#### 2 Decision-theoretic case-based reasoning

*Breese, J.S.; Heckerman, D.;*

Systems, Man and Cybernetics, Part A, IEEE Transactions on , Volume: 26 , I  
6 , Nov. 1996

Pages:838 - 842

[\[Abstract\]](#) [\[PDF Full-Text \(552KB\)\]](#) **IEEE JNL**

#### 3 Causal independence for probability assessment and inference using Bayesian networks

*Heckerman, D.; Breese, J.S.;*

Systems, Man and Cybernetics, Part A, IEEE Transactions on , Volume: 26 , I  
6 , Nov. 1996

Pages:826 - 831

[\[Abstract\]](#) [\[PDF Full-Text \(604KB\)\]](#) **IEEE JNL**

#### 4 An approximate nonmyopic computation for value of information

*Heckerman, D.; Horvitz, E.; Middleton, B.;*

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume:  
15 , Issue: 3 , March 1993

Pages:292 - 298

[\[Abstract\]](#) [\[PDF Full-Text \(604KB\)\]](#) **IEEE JNL**

#### 5 Separating appearance from deformation

*Jojic, N.; Simard, P.; Frey, B.J.; Heckerman, D.;*

Computer Vision, 2001. ICCV 2001. Proceedings. Eighth IEEE International  
Conference on , Volume: 2 , 7-14 July 2001

Pages:288 - 294 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(788KB\)\]](#) **IEEE CNF**

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**1 On compatible priors for Bayesian networks**

*Cowell, R.G.;*

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 18 , Issue: 9 , Sept. 1996

Pages:901 - 911

[\[Abstract\]](#)   [\[PDF Full-Text \(916KB\)\]](#)   **IEEE JNL**

**2 Sequential model criticism in probabilistic expert systems**

*Cowell, R.G.; Dawid, A.P.; Spiegelhalter, D.J.;*

Pattern Analysis and Machine Intelligence, IEEE Transactions on , Volume: 15 , Issue: 3 , March 1993

Pages:209 - 219

[\[Abstract\]](#)   [\[PDF Full-Text \(904KB\)\]](#)   **IEEE JNL**



## Refine Search

### Search Results -

Terms	Documents
L10 and sequence and resolution	7

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<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>
<u>L1</u>	6,535,865.pn.	2	<u>L1</u>

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Search Results - Record(s) 1 through 9 of 9 returned.

☐ 1. Document ID: US 5751915 A

Using default format because multiple data bases are involved.

L7: Entry 1 of 9

File: USPT

May 12, 1998

US-PAT-NO: 5751915

DOCUMENT-IDENTIFIER: US 5751915 A

TITLE: Elastic fuzzy logic system

DATE-ISSUED: May 12, 1998

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Werbos; Paul J.	College Park	MD	20740	

US-CL-CURRENT: 706/4; 706/2, 706/52

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachment	Claims	KMC	Draw D
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☐ 2. Document ID: US 5604841 A

L7: Entry 2 of 9

File: USPT

Feb 18, 1997

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: 706/11; 706/52

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachment	Claims	KMC	Draw D
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☐ 3. Document ID: US 5537644 A

L7: Entry 3 of 9

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using  
qualitative physics

DATE-ISSUED: July 16, 1996

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		

US-CL-CURRENT: 706/52; 702/33, 702/35

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Draw. De
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☐ 4. Document ID: US 5522014 A

L7: Entry 4 of 9

File: USPT

May 28, 1996

US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

**\*\* See image for Certificate of Correction \*\***

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core  
predictions and extended test procedures for machine failure isolation using  
qualitative physics

DATE-ISSUED: May 28, 1996

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Clark; Robert T.	Enfield	CT		
Hamilton; Thomas P.	South Windsor	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMC	Draw. De
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☐ 5. Document ID: US 5353381 A

L7: Entry 5 of 9

File: USPT

Oct 4, 1994

US-PAT-NO: 5353381  
DOCUMENT-IDENTIFIER: US 5353381 A

TITLE: Intelligent test selection for machine failure isolation using qualitative physics

DATE-ISSUED: October 4, 1994

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Perveiler; Kevin J.	Monroe	CT		
Jacobsen; Carol E.	Shelton	CT		

US-CL-CURRENT: 706/52

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 6. Document ID: US 5216749 A

L7: Entry 6 of 9

File: USPT

Jun 1, 1993

US-PAT-NO: 5216749  
DOCUMENT-IDENTIFIER: US 5216749 A

TITLE: Core predictions for qualitative physics

DATE-ISSUED: June 1, 1993

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 7. Document ID: US 5202955 A

L7: Entry 7 of 9

File: USPT

Apr 13, 1993

US-PAT-NO: 5202955  
DOCUMENT-IDENTIFIER: US 5202955 A

TITLE: Dynamic assumption ordering for qualitative physics

DATE-ISSUED: April 13, 1993

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
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Hamilton; Thomas P. South Windsor CT  
Jacobsen; Carol E. Shelton CT

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw De
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☐ 8. Document ID: US 5187773 A

L7: Entry 8 of 9

File: USPT

Feb 16, 1993

US-PAT-NO: 5187773

DOCUMENT-IDENTIFIER: US 5187773 A

**\*\* See image for Certificate of Correction \*\***

TITLE: Machine failure isolation using qualitative physics

DATE-ISSUED: February 16, 1993

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Jacobsen; Carol E.	Shelton	CT		
Perveiler; Kevin J.	Monroe	CT		

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw De
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☐ 9. Document ID: US 5138694 A

L7: Entry 9 of 9

File: USPT

Aug 11, 1992

US-PAT-NO: 5138694

DOCUMENT-IDENTIFIER: US 5138694 A

TITLE: Parallel processing qualitative reasoning system

DATE-ISSUED: August 11, 1992

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windosr	CT		

US-CL-CURRENT: 706/52; 706/10

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw De
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☐ 1. Document ID: US 5604841 A

Using default format because multiple data bases are involved.

L8: Entry 1 of 3

File: USPT

Feb 18, 1997

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: 706/11; 706/52

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawings
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☐ 2. Document ID: US 5537644 A

L8: Entry 2 of 3

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using qualitative physics

DATE-ISSUED: July 16, 1996

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Hamilton; Thomas P.	South Windsor	CT		
Clark; Robert T.	Enfield	CT		

US-CL-CURRENT: 706/52; 702/33, 702/35

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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☐ 3. Document ID: US 5522014 A

L8: Entry 3 of 3

File: USPT

May 28, 1996

US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

**\*\* See image for Certificate of Correction \*\***

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core predictions and extended test procedures for machine failure isolation using qualitative physics

DATE-ISSUED: May 28, 1996

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Clark; Robert T.	Enfield	CT		
Hamilton; Thomas P.	South Windsor	CT		
Gallo; Steven	Vernon	CT		

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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3

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Search Results - Record(s) 1 through 2 of 2 returned.

☐ 1. Document ID: US 20020116351 A1

Using default format because multiple data bases are involved.

L9: Entry 1 of 2

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	CO	DK	
Wright, David W.	Fort Collins		US	

US-CL-CURRENT: 706/21

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw. De
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☐ 2. Document ID: US 6012152 A

L9: Entry 2 of 2

File: USPT

Jan 4, 2000

US-PAT-NO: 6012152

DOCUMENT-IDENTIFIER: US 6012152 A

**\*\* See image for Certificate of Correction \*\***

TITLE: Software fault management system

DATE-ISSUED: January 4, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Douik; Samir	Sainte Anne de Bellevue			CA
Boutaba; Raouf	Montreal			CA

US-CL-CURRENT: 714/26

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw D
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<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
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<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>
<u>L1</u>	6,535,865.pn.	2	<u>L1</u>

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☐ 1. Document ID: US 20030167111 A1

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L14: Entry 1 of 16

File: PGPB

Sep 4, 2003

PGPUB-DOCUMENT-NUMBER: 20030167111

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030167111 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 4, 2003

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Kipersztok, Oscar	Redmond	WA	US	
Rein-Weston, Karl J.	Seattle	WA	US	
Nelson, Scott L.	Issaquah	WA	US	
Dildy, Glenn A.	Sammamish	WA	US	
Chew, Susan Chan	Issaquah	WA	US	

US-CL-CURRENT: 701/29; 702/185, 714/25

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw De
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☐ 2. Document ID: US 20020183988 A1

L14: Entry 2 of 16

File: PGPB

Dec 5, 2002

PGPUB-DOCUMENT-NUMBER: 20020183988

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020183988 A1

TITLE: Model selection for decision support systems

PUBLICATION-DATE: December 5, 2002

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	CO	DK	
Schreckengast, James	Fort Collins		US	

US-CL-CURRENT: 703/2

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMIC	Draw. De
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☐ 3. Document ID: US 20020138184 A1

L14: Entry 3 of 16

File: PGPB

Sep 26, 2002

PGPUB-DOCUMENT-NUMBER: 20020138184

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020138184 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 26, 2002

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Kipersztok, Oscar	Redmond	WA	US	
Rein-Weston, Karl J.	Seattle	WA	US	
Walker, Nicholas James	Seattle	WA	US	
Chew, Susan Chan	Issaquah	WA	US	

US-CL-CURRENT: 701/29; 340/945

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMIC	Draw. De
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☐ 4. Document ID: US 20020116351 A1

L14: Entry 4 of 16

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	CO	DK	
Wright, David W.	Fort Collins		US	

US-CL-CURRENT: 706/21

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KMIC	Draw. De
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☐ 5. Document ID: US 20020044296 A1

L14: Entry 5 of 16

File: PGPB

Apr 18, 2002

PGPUB-DOCUMENT-NUMBER: 20020044296

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020044296 A1

TITLE: Authoring tool for bayesian network diagnostic systems

PUBLICATION-DATE: April 18, 2002

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund		DK	

US-CL-CURRENT: 358/1.14; 358/1.15

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawn De
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☐ 6. Document ID: US 20010011260 A1

L14: Entry 6 of 16

File: PGPB

Aug 2, 2001

PGPUB-DOCUMENT-NUMBER: 20010011260

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20010011260 A1

TITLE: Automated diagnosis of printer systems using bayesian networks

PUBLICATION-DATE: August 2, 2001

## INVENTOR-INFORMATION:

NAME	CITY	STATE	COUNTRY	RULE-47
Skaanning, Claus	Dronninglund	ID	DK	
Jensen, Finn V.	Broenderslev	ID	DK	
Kjaerulff, Uffe	Aalborg		DK	
Pelletier, Paul A.	Boise		US	
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Bogorad, Janice L.	Allerod		DK	

US-CL-CURRENT: 706/46

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawn De
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☐ 7. Document ID: US 6591257 B1

L14: Entry 7 of 16

File: USPT

Jul 8, 2003

US-PAT-NO: 6591257  
DOCUMENT-IDENTIFIER: US 6591257 B1

TITLE: Apparatus and method for a compositional decision support reasoning system

DATE-ISSUED: July 8, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Martinka; Joseph J	Sunnyvale	CA		
Collins; Patricia	Mountain View	CA		
Forman; George H.	Port Orchard	WA		
Kirshenbaum; Evan R.	Mountain View	CA		
Seetharaman; Aparna	Palo Alto	CA		

US-CL-CURRENT: 706/46

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw D
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☐ 8. Document ID: US 6574537 B2

L14: Entry 8 of 16

File: USPT

Jun 3, 2003

US-PAT-NO: 6574537  
DOCUMENT-IDENTIFIER: US 6574537 B2

TITLE: Diagnostic system and method

DATE-ISSUED: June 3, 2003

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Kipersztok; Oscar	Redmond	WA		
Rein-Weston; Karl J.	Seattle	WA		
Nelson; Scott L.	Issaquah	WA		
Dildy; Glenn A.	Sammamish	WA		
Walker; Nicholas James	Seattle	WA		
Chew; Susan Chan	Issaquah	WA		

US-CL-CURRENT: 701/29; 701/33, 701/34, 702/185, 714/25

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWC	Draw D
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☐ 9. Document ID: US 6484010 B1

L14: Entry 9 of 16

File: USPT

Nov 19, 2002

US-PAT-NO: 6484010  
DOCUMENT-IDENTIFIER: US 6484010 B1

**\*\* See image for Certificate of Correction \*\***

TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 19, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Sheehan; Kathleen M.	Skillman	NJ		

US-CL-CURRENT: [434/362](#); [434/118](#), [434/322](#), [434/350](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachment	Claims	KWIC	Draw De
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☐ 10. Document ID: US 6394952 B1

L14: Entry 10 of 16

File: USPT

May 28, 2002

US-PAT-NO: 6394952

DOCUMENT-IDENTIFIER: US 6394952 B1

**\*\* See image for Certificate of Correction \*\***

TITLE: Point of care diagnostic systems

DATE-ISSUED: May 28, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Anderson; Emory V.	Danville	CA		
Lapointe; Jerome	Oakland	CA		
Martinez; Ricardo	Santa Cruz	CA		
Marzolf; Gail	Cupertino	CA		
Pong; Ronald	San Jose	CA		
Jones; Lynn	Mountainview	CA		
Hussa; Robert O.	Sunnyvale	CA		
Nemec; Edward	Duluth	GA		
Senyei; Andrew E.	La Jolla	CA		
DeSieno; Duane	La Jolla	CA		

US-CL-CURRENT: [600/300](#); [435/4](#), [436/814](#), [600/304](#), [600/310](#), [600/351](#), [600/573](#), [600/584](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachment	Claims	KWIC	Draw De
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☐ 11. Document ID: US 6267722 B1

L14: Entry 11 of 16

File: USPT

Jul 31, 2001

US-PAT-NO: 6267722

DOCUMENT-IDENTIFIER: US 6267722 B1

**\*\* See image for Certificate of Correction \*\***

TITLE: Point of care diagnostic systems

DATE-ISSUED: July 31, 2001

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Anderson; Emory V.	Danville	CA		
Nemec; Edward	Duluth	GA		
Lapointe; Jerome	Oakland	CA		
DeSieno; Duane	La Jolla	CA		
Martinez; Ricardo	Santa Cruz	CA		
Marzolf; Gail	Cupertino	CA		
Pong; Ronald	San Jose	CA		
Jones; Lynn	Mountain View	CA		
Hussa; Robert O.	Sunnyvale	CA		
Senyei; Andrew E.	La Jolla	CA		

US-CL-CURRENT: 600/300; 435/4, 436/811, 436/814, 600/304, 600/310, 600/345,  
600/573, 600/584

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw De
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☐ 12. Document ID: US 6219626 B1

L14: Entry 12 of 16

File: USPT

Apr 17, 2001

US-PAT-NO: 6219626

DOCUMENT-IDENTIFIER: US 6219626 B1

**\*\* See image for Certificate of Correction \*\***

TITLE: Automated diagnostic system

DATE-ISSUED: April 17, 2001

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Steinmetz; Michael J.	Kissimmee	FL	34743	
Kirst; Michael E.	Kissimmee	FL	34744	

US-CL-CURRENT: 702/183; 702/182, 702/185, 714/25, 714/46

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWIC	Draw De
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☐ 13. Document ID: US 6144838 A

L14: Entry 13 of 16

File: USPT

Nov 7, 2000

US-PAT-NO: 6144838

DOCUMENT-IDENTIFIER: US 6144838 A



TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 7, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Sheehan; Kathleen M.	Skillman	NJ		

US-CL-CURRENT: [434/362](#); [434/118](#), [434/322](#), [434/350](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWMC	Draw D
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☒ 14. Document ID: US 6076083 A

L14: Entry 14 of 16

File: USPT

Jun 13, 2000

US-PAT-NO: 6076083

DOCUMENT-IDENTIFIER: US 6076083 A

TITLE: Diagnostic system utilizing a Bayesian network model having link weights updated experimentally

DATE-ISSUED: June 13, 2000

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Baker; Michelle	New York	NY	10025	

US-CL-CURRENT: [706/52](#); [706/45](#), [706/46](#), [706/61](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequence	Attachments	Claims	KWMC	Draw D
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☐ 15. Document ID: US 5544308 A

L14: Entry 15 of 16

File: USPT

Aug 6, 1996

US-PAT-NO: 5544308

DOCUMENT-IDENTIFIER: US 5544308 A

TITLE: Method for automating the development and execution of diagnostic reasoning software in products and processes

DATE-ISSUED: August 6, 1996

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Giordano; Gerard J.	Sparta	NJ		
deMare; Gregory	Sparta	NJ		
Longendorfer; Betsy	Ridgewood	NJ		
Granieri; Michael N.	Springfield	VA		

Giordano; John P.	Sparta	NJ
Nolan; Mary E.	Lafayette	NJ
Levy; Ford	Pleasantville	NY

US-CL-CURRENT: [714/26](#); [706/45](#), [706/912](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	References	Attachments	Claims	KMC	Draw De
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☐ 16. Document ID: US 5130936 A

L14: Entry 16 of 16

File: USPT

Jul 14, 1992

US-PAT-NO: 5130936

DOCUMENT-IDENTIFIER: US 5130936 A

TITLE: Method and apparatus for diagnostic testing including a neural network for determining testing sufficiency

DATE-ISSUED: July 14, 1992

## INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE	COUNTRY
Sheppard; John W.	Glen Burnie	MD		
Simpson; William R.	Edgewater	MD		
Graham; Jerry L.	Baldwin	MD		

US-CL-CURRENT: [702/123](#); [128/925](#), [324/73.1](#), [706/10](#), [706/20](#), [706/911](#)

Full	Title	Citation	Front	Review	Classification	Date	Reference	References	Attachments	Claims	KMC	Draw De
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**1 Construction of Bayesian networks for diagnostics**

*Przytula, K.W.; Thompson, D.;*

Aerospace Conference Proceedings, 2000 IEEE , Volume: 5 , 18-25 March 2000  
 Pages:193 - 200 vol.5

[\[Abstract\]](#)   [\[PDF Full-Text \(688 KB\)\]](#)   **IEEE CNF**

**2 Constructing Bayesian networks for medical diagnosis from incomplete and partially correct statistics**

*Nikovski, D.;*

Knowledge and Data Engineering, IEEE Transactions on , Volume: 12 , Issue: 4 , July-Aug. 2000  
 Pages:509 - 516

[\[Abstract\]](#)   [\[PDF Full-Text \(160 KB\)\]](#)   **IEEE JNL**

**3 A probabilistic approach to residual processing for vehicle fault detection**

*Schwall, M.L.; Gerdes, J.C.;*

American Control Conference, 2002. Proceedings of the 2002 , Volume: 3 , 8-10 May 2002  
 Pages:2552 - 2557 vol.3

[\[Abstract\]](#)   [\[PDF Full-Text \(614 KB\)\]](#)   **IEEE CNF**

**4 A smart diagnostic system for Doppler ultrasonography**

*Das, B.; Banerjee, S.;*

Bioengineering Conference, 2002. Proceedings of the IEEE 28th Annual Northeast , 20-21 April 2002  
 Pages:275 - 276

[\[Abstract\]](#)   [\[PDF Full-Text \(333 KB\)\]](#)   IEEE CNF

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**5 Extending the feature dictionary to support sophisticated feature interaction and classification**

*Samuels, W.B.; Evens, M.; Naeymi-Rad, F.; Rosenthal, R.; Naeymirad, S.; Le Trace, D.; Carmony, L.;*

Computer-Based Medical Systems, 1989. Proceedings., Second Annual IEEE Symposium on , 26-27 June 1989

Pages:29 - 35

[\[Abstract\]](#)   [\[PDF Full-Text \(524 KB\)\]](#)   IEEE CNF

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**6 Summary and applicability of analog fault detection/isolation techn**

*Molnar, J.A.;*

AUTOTESTCON '97. 1997 IEEE Autotestcon Proceedings , 22-25 Sept. 1997

Pages:383 - 389

[\[Abstract\]](#)   [\[PDF Full-Text \(608 KB\)\]](#)   IEEE CNF

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